

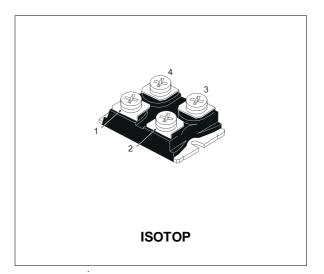
# **ESM2030DV**

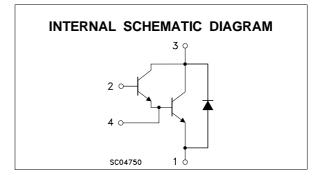
## NPN DARLINGTON POWER MODULE

- HIGH CURRENT POWER BIPOLAR MODULE
- VERY LOW Rth JUNCTION CASE
- SPECIFIED ACCIDENTAL OVERLOAD AREAS
- ULTRAFAST FREEWHEELING DIODE
- FULLY INSULATED PACKAGE (UL COMPLIANT)
- EASY TO MOUNT
- LOW INTERNAL PARASITIC INDUCTANCE -

#### **INDUSTRIAL APPLICATIONS:**

- MOTOR CONTROL
- UPS
- DC/DC & DC/AC CONVERTERS





#### **ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Value	Unit
VCEV	Collector-Emitter Voltage (V <sub>BE</sub> = -5 V)	400	V
V <sub>CEO(sus)</sub>	Collector-Emitter Voltage $(I_B = 0)$	300	V
VEBO	Emitter-Base Voltage (I <sub>C</sub> = 0)	7	V
lc	Collector Current	67	А
Ісм	Collector Peak Current (t <sub>p</sub> = 10 ms)	100	А
lв	Base Current	3	А
I <sub>BM</sub>	Base Peak Current (t <sub>p</sub> = 10 ms)	6	А
P <sub>tot</sub>	Total Dissipation at $T_c = 25 \ ^{\circ}C$	150	W
Visol	Insulation Withstand Voltage (RMS) from All Four Terminals to Exernal Heatsink	2500	V
T <sub>stg</sub>	Storage Temperature	-55 to 150	°C
Tj	Max. Operating Junction Temperature	150	°C
eptember	2003		1

### THERMAL DATA

R <sub>thj-case</sub>	Thermal Resistance Junction-case (transistor)	Max	0.83	°C/W
R <sub>thj</sub> -case	Thermal Resistance Junction-case (diode)	Max	1.2	°C/W
R <sub>thc-h</sub>	Thermal Resistance Case-heatsink With Conductive			
	Grease Applied	Max	0.05	°C/W

### **ELECTRICAL CHARACTERISTICS** ( $T_{case} = 25 \ ^{\circ}C$ unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I <sub>CER</sub> #	Collector Cut-off Current ( $R_{BE} = 5 \Omega$ )				1.5 16	mA mA
I <sub>CEV</sub> #	Collector Cut-off Current (V <sub>BE</sub> = -5V)	$V_{CE} = V_{CEV}$ $V_{CE} = V_{CEV}$ $T_j = 100 \ ^{\circ}C$			1 11	mA mA
I <sub>EBO</sub> #	Emitter Cut-off Current $(I_C = 0)$	V <sub>EB</sub> = 5 V			1	mA
Vceo(sus)*	Collector-Emitter Sustaining Voltage	$I_C = 0.2 A$ $L = 25 mH$ $V_{clamp} = 300 V$	300			V
h <sub>FE</sub> *	DC Current Gain	I <sub>C</sub> = 56 A V <sub>CE</sub> = 5 V		300		
V <sub>CE(sat)</sub> *	Collector-Emitter Saturation Voltage			1.25 1.4 1.5 1.8	1.8 2.2	V V V V
$V_{BE(sat)^*}$	Base-Emitter Saturation Voltage	$      I_{C} = 56 \ A  I_{B} = 1.6 \ A \\ I_{C} = 56 \ A  I_{B} = 1.6 \ A  T_{j} = 100 \ ^{o}C $		2.4 2.5	3	V V
di <sub>C</sub> /dt	Rate of Rise of On-state Collector		220	260		A/μs
V <sub>CE</sub> (3 µs)⊷	Collector-Emitter Dynamic Voltage			3	6	V
V <sub>CE</sub> (5 μs)••	Collector-Emitter Dynamic Voltage			2.2	4	V
t <sub>s</sub> t <sub>f</sub> t <sub>c</sub>	Storage Time Fall Time Cross-over Time			2 0.35 0.8	3 0.6 1.2	μs μs μs
V <sub>CEW</sub>	Maximum Collector Emitter Voltage Without Snubber	$      I_{CWoff} = 67 A \qquad I_{B1} = 1.6 A \\ V_{BB} = -5 V \qquad V_{CC} = 50 V \\ L = 0.037 \text{ mH} \qquad R_{BB} = 0.6 \Omega \\ T_j = 125 \ ^{\circ}C $	300			V
V <sub>F</sub> *	Diode Forward Voltage	$I_F = 56 \text{ A}$ $T_j = 100 \text{ °C}$		1.15	1.6	V
I <sub>RM</sub>	Reverse Recovery Current	V <sub>CC</sub> = 200 V I <sub>F</sub> = 56 A di <sub>F</sub> /dt = -220 A/μs L < 0.05 μH T <sub>j</sub> = 100 °C		12	17	A

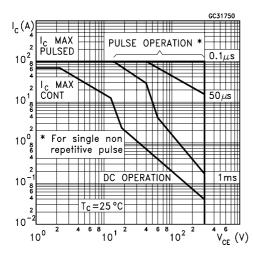
\* Pulsed: Pulse duration = 300  $\mu$ s, duty cycle 1.5 %

# See test circuit in databook introduction

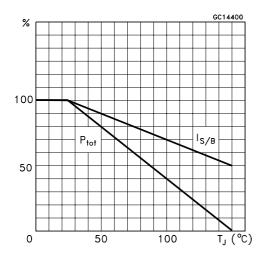
To evaluate the conduction losses of the diode use the following equations:  $V_F = 1.1 + 0.0045 I_F$  P = 1.1  $I_{F(AV)} + 0.0045 I^2_{F(RMS)}$ 

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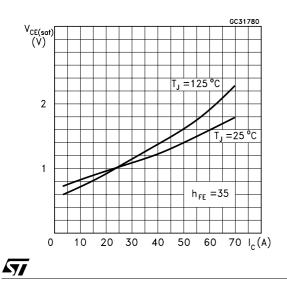
#### Safe Operating Areas



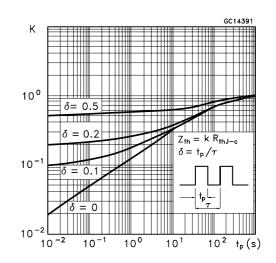
#### **Derating Curve**



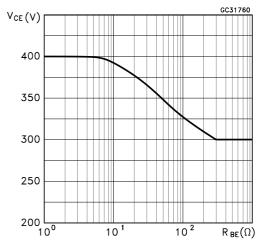
Collector Emitter Saturation Voltage



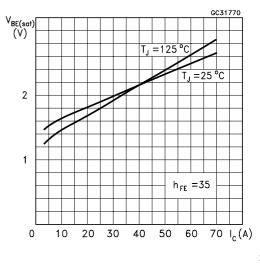
Thermal Impedance



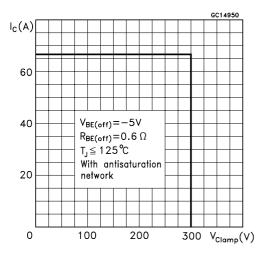
# Collector-emitter Voltage Versus base-emitter Resistance



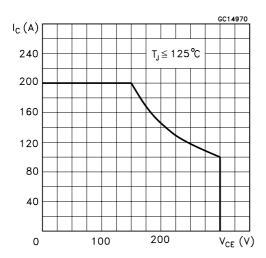




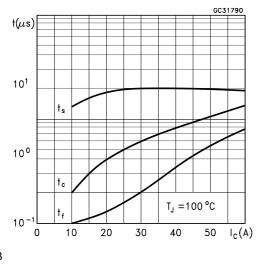
#### **Reverse Biased SOA**



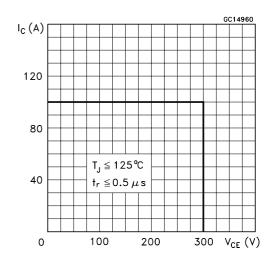
**Reverse Biased AOA** 



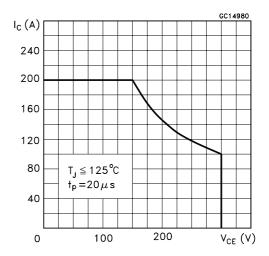
Switching Times Inductive Load



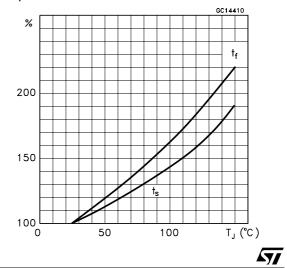
Foward Biased SOA



#### Forward Biased AOA

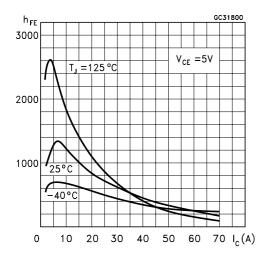


Switching Times Inductive Load Versus Temperature

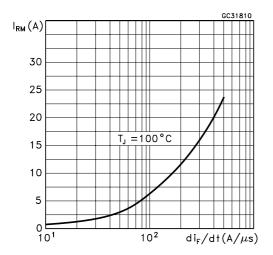


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#### Dc Current Gain

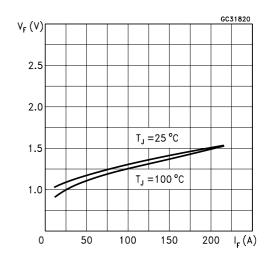


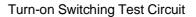
Peak Reverse Current Versus diF/dt

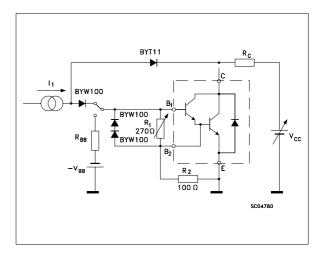


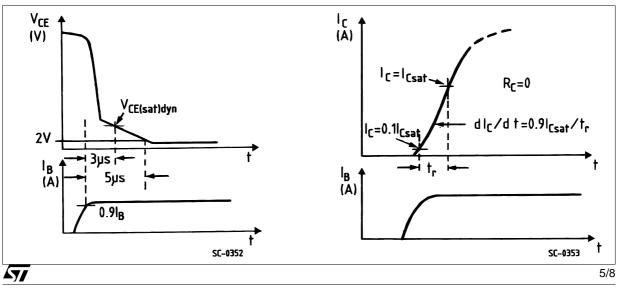


Typical V<sub>F</sub> Versus I<sub>F</sub>

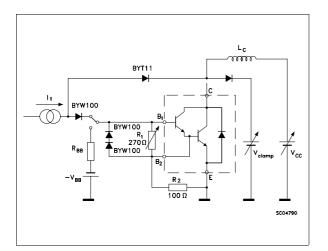




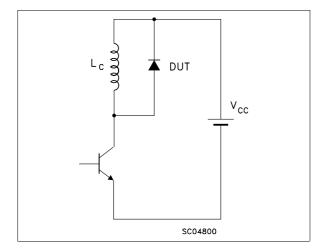




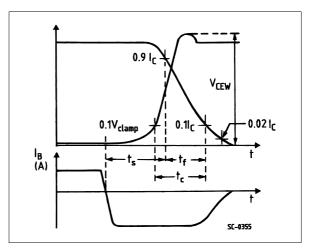
### Turn-on Switching Test Circuit



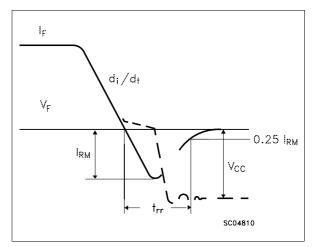
Turn-off Switching Test Circuit of Diode



Turn-off Switching Waveforms



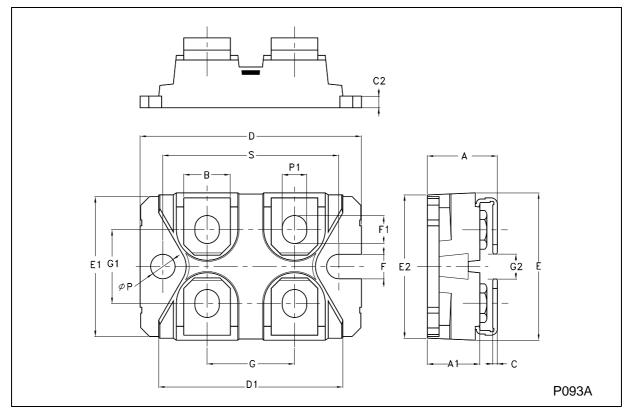
Turn-off Switching Waveform of Diode



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DIM.		mm		inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	11.8		12.2	0.465		0.480
A1	8.9		9.1	0.350		0.358
В	7.8		8.2	0.307		0.322
С	0.75		0.85	0.029		0.033
C2	1.95		2.05	0.076		0.080
D	37.8		38.2	1.488		1.503
D1	31.5		31.7	1.240		1.248
Е	25.15		25.5	0.990		1.003
E1	23.85		24.15	0.938		0.950
E2		24.8			0.976	
G	14.9		15.1	0.586		0.594
G1	12.6		12.8	0.496		0.503
G2	3.5		4.3	0.137		1.169
F	4.1		4.3	0.161		0.169
F1	4.6		5	0.181		0.196
Р	4		4.3	0.157		0.169
P1	4		4.4	0.157		0.173
P1 S	4 30.1		4.4 30.3	0.157		0





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